

of 5 to 750 MeV/u Heavy Ion Beams

F. Becker¹, C. Andre¹, P. Forck¹, D.H.H. Hoffmann^{1,2}

1) Gesellschaft für Schwerionenforschung mbH GSI, Darmstadt
2) Technische Universität Darmstadt







Outline



Introduction

- Detectors for high beam power
- BIF-detection principle

Experiment

- Setup
- Data Analysis
- Results

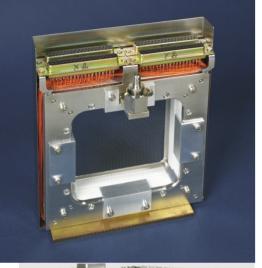
Conclusion

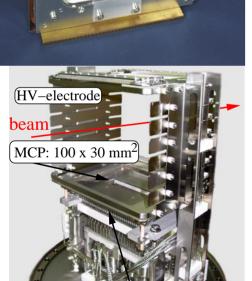






Comparison of Profile Monitors





Secondary-Electron-Monitor (SEM) Grid

- + Standard tool, compact design
- + Low background level
- Limited spacial resolution (wire spacing)
- -- Melts in high power beams!

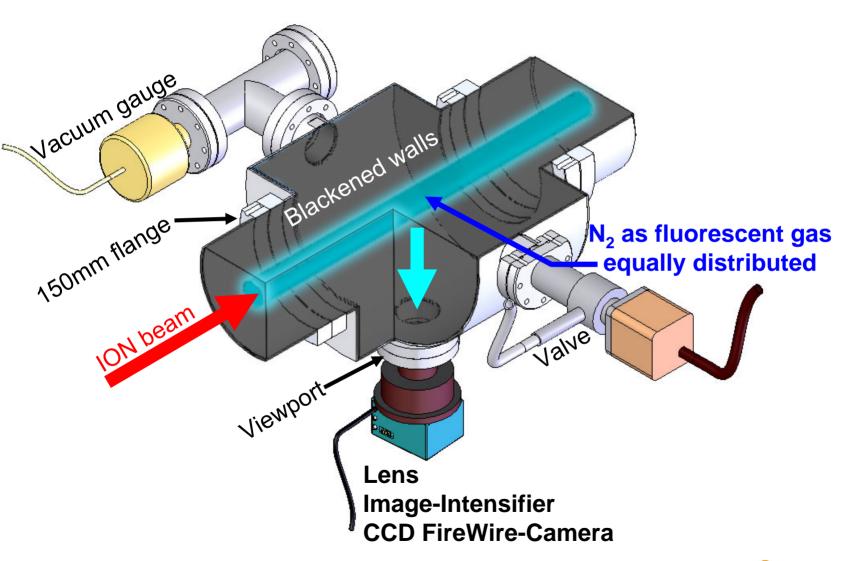
Residual Gas Monitor (RGM)

- + Non-intercepting monitoring
- + Measures even high power beams
- + Very sensitive \mapsto used in synchrotrons
- Lot of mechanics inside vacuum



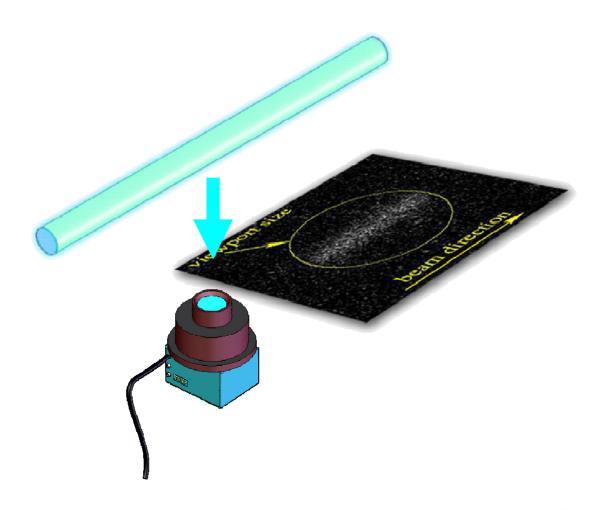


Beam Induced Fluorescence (BIF)



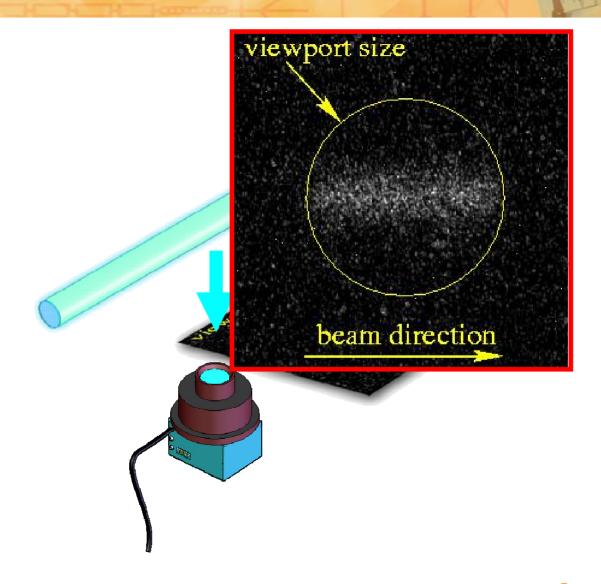


How a Profile is obtained



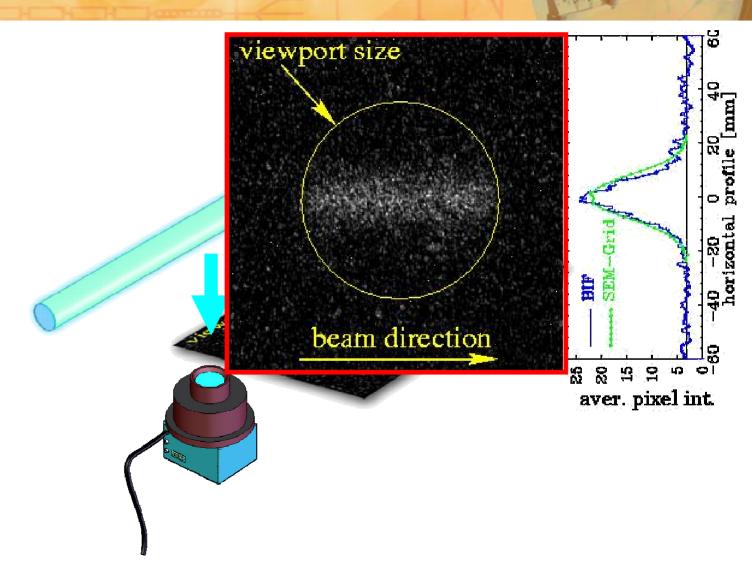


How a Profile is obtained





How a Profile is obtained

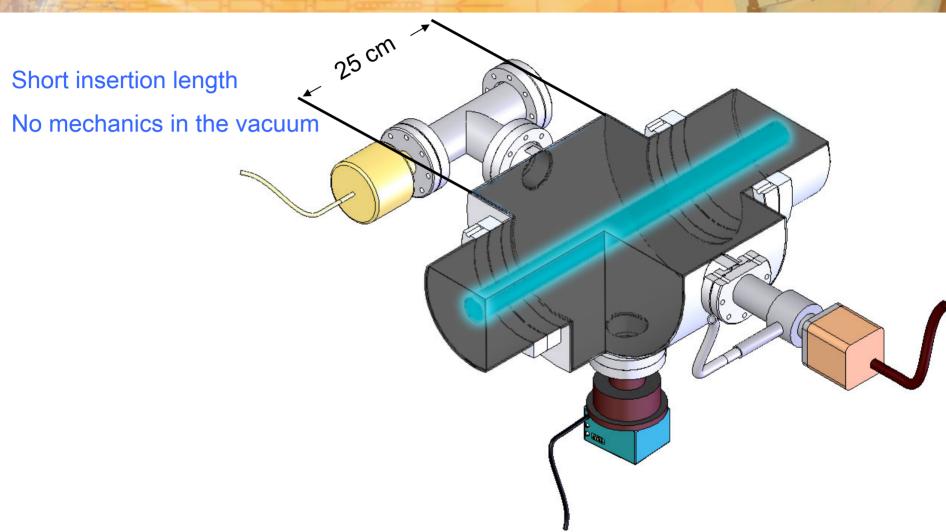






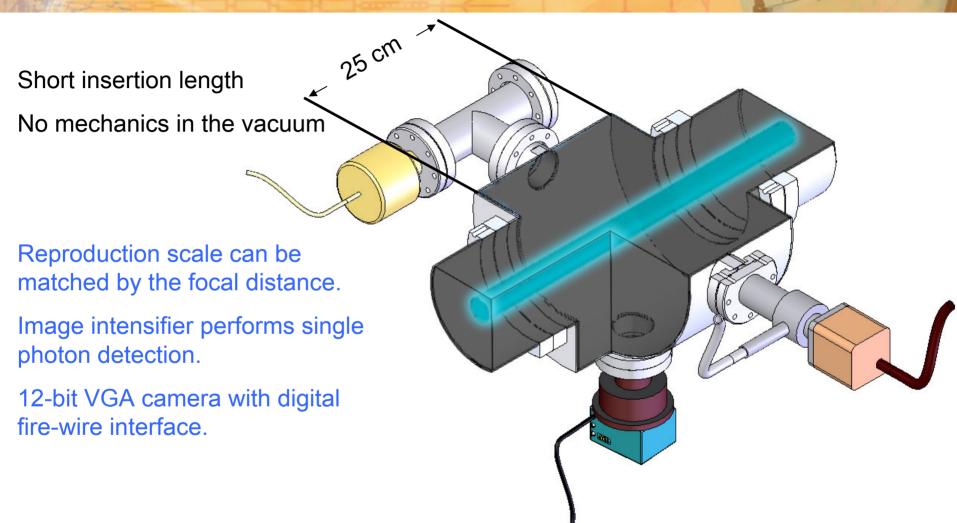


Advantages of BIF





Advantages of BIF





Advantages of BIF

Short insertion length

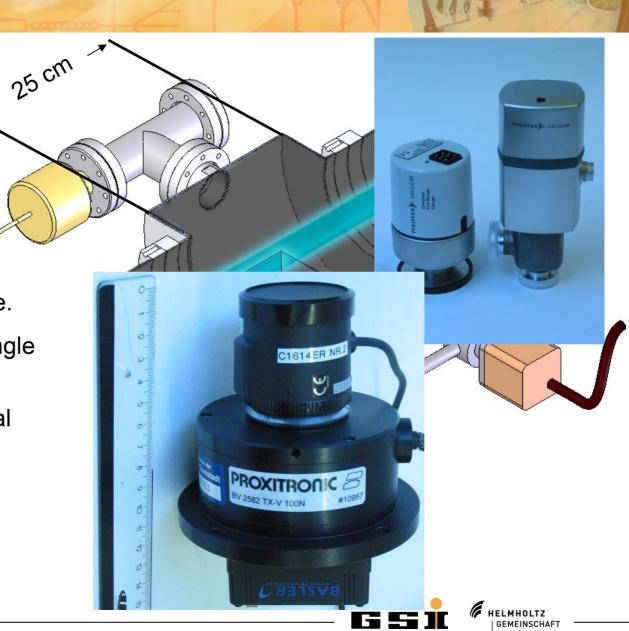
No mechanics in the vacuum

Reproduction scale can be matched by the focal distance.

Image intensifier performs single photon detection.

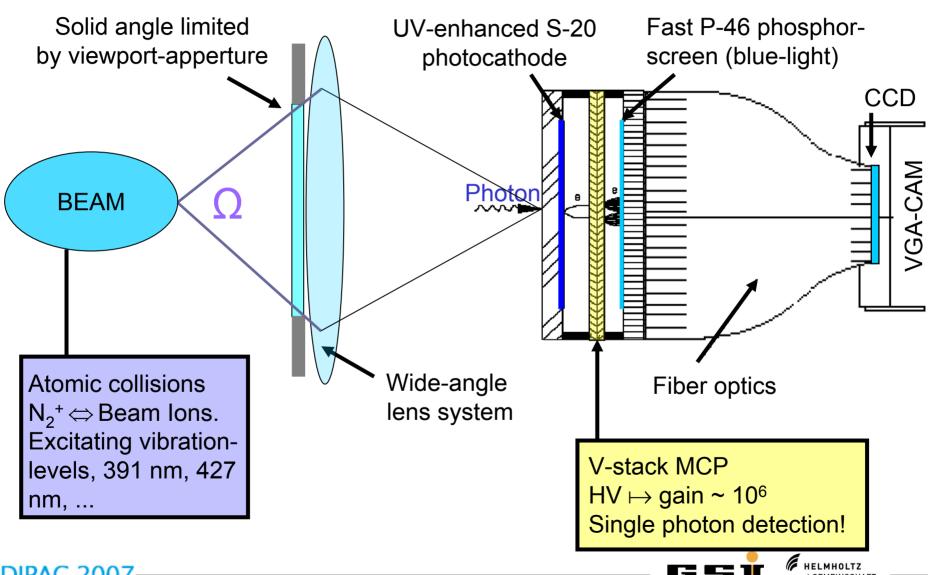
12-bit VGA camera with digital fire-wire interface.

Commercial Components



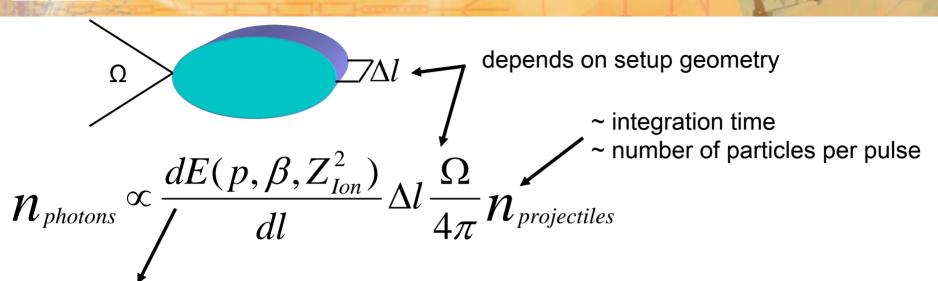


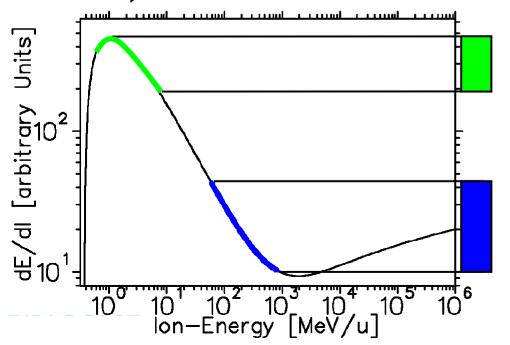
Detection Principle





Expected Photon Yield





LINAC:

High energy loss typical: 5-11 MeV/u 2,5 mA ~ 10¹² particles pp.

SYNC/ HEBT:

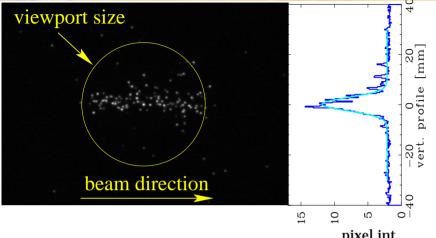
Low energy loss typical: 60-2000 MeV/u 10¹⁰ particles per cycle



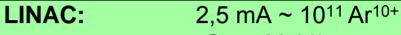


Areas of Application





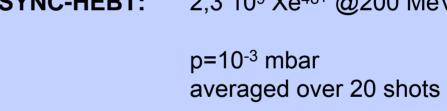
Detection-efficiency adjusted by pressure



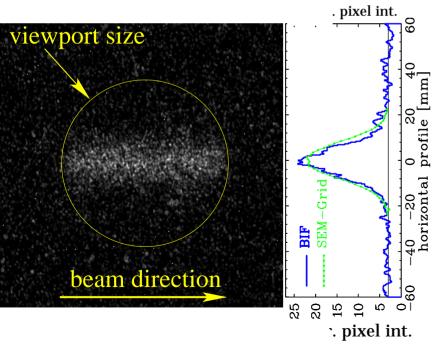
@4,4 MeV/u

p=5 10⁻⁶ mbar single shot

SYNC-HEBT: 2,3 10⁹ Xe⁴⁸⁺ @200 MeV/u



- Background is larger at HEBT energies
- + Application had been proven!



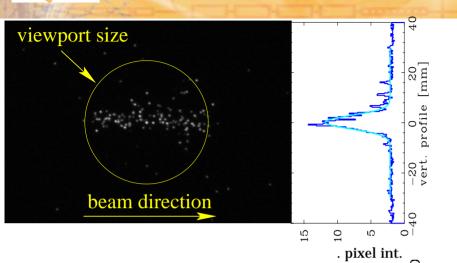




viewport size

Areas of Application





Detection-efficiency adjusted by pressure

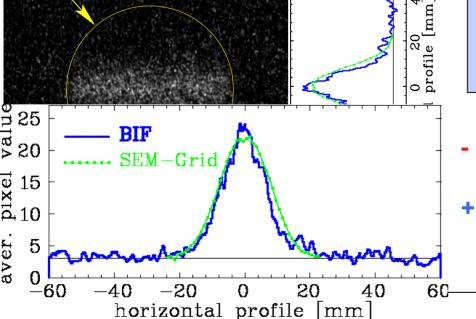


p=5 10⁻⁶ mbar single shot

SYNC-HEBT: 2,3 10⁹ Xe⁴⁸⁺ @200 MeV/u

> $p=10^{-3}$ mbar averaged over 20 shots

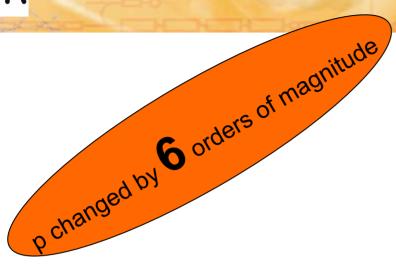
- Background is larger at HEBT energies
- + Application had been proven!

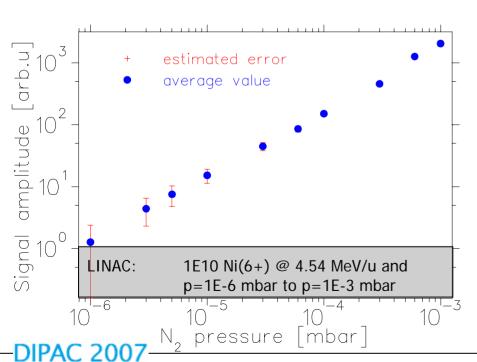


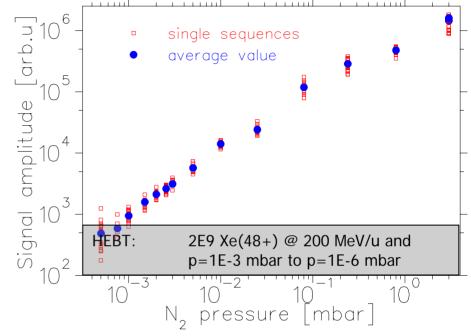




Pressure Variation





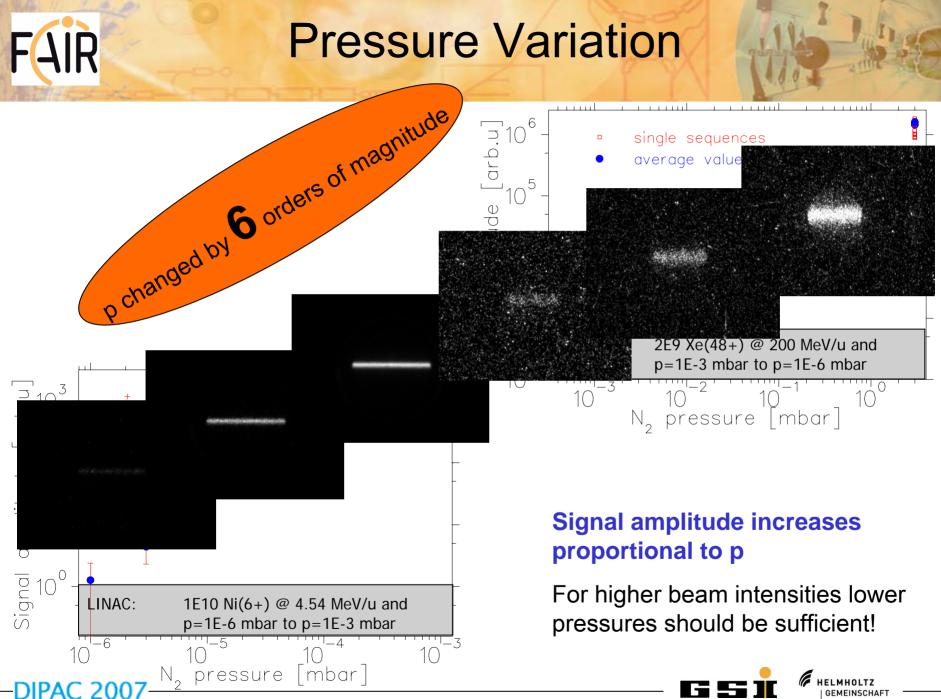


Signal amplitude increases proportional to p

For higher beam intensities lower pressures should be sufficient!





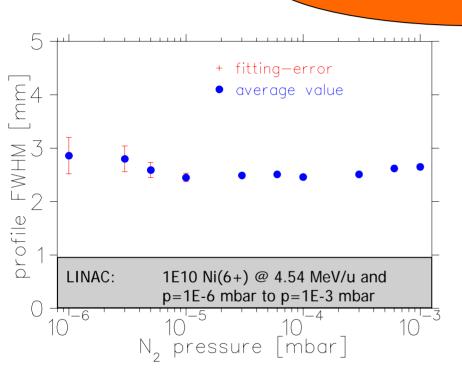


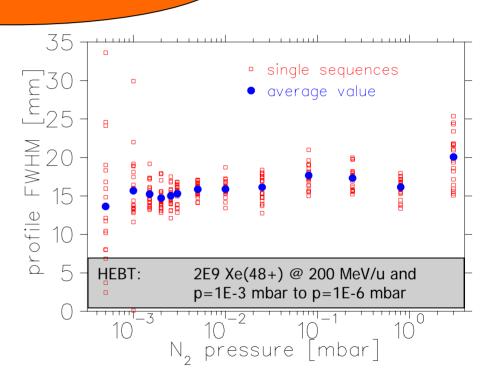


Pressure Variation



p changed by 6 orders of magnitude



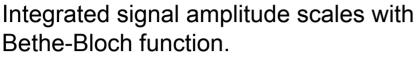


Profile width remains constant \rightarrow p is suitable parameter to match signal strength!





Energy Variation



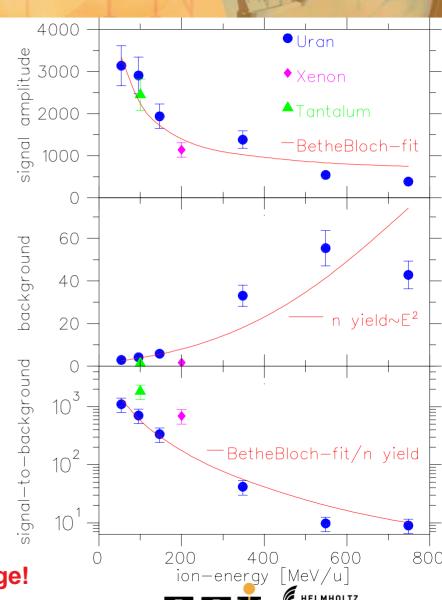
Good accordance for all ions normalized by their charge and mass with respect to U⁷³⁺

Background level encreases with approximately E².

It is generated by thermal **NEUTRONS** hitting the photo-cathode.

Signal to background ratio decreases two oders of magnitude.

Short gating during fast extraction improves the ratio by a factor 4, for Xe and Ta.

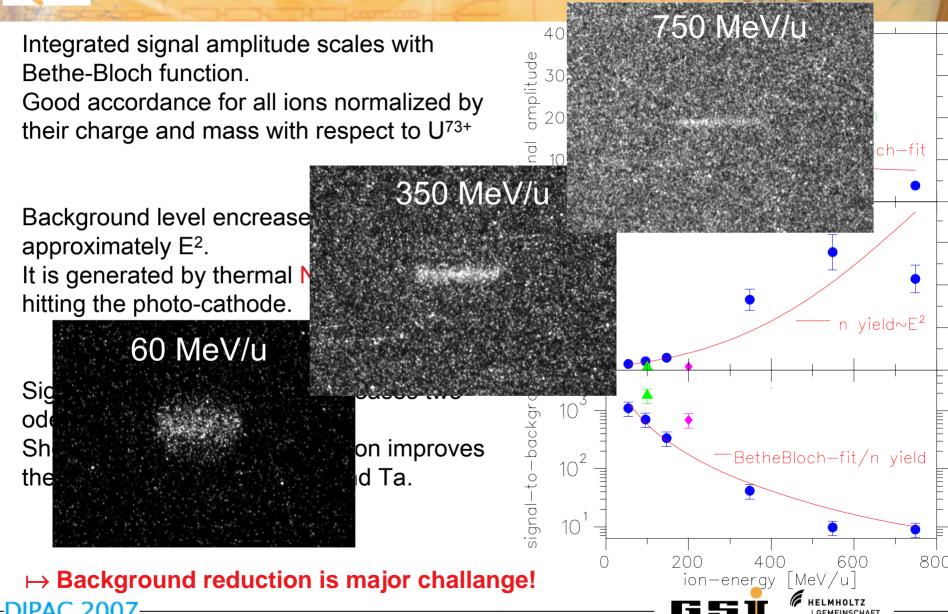


→ Background reduction is major challange!

DIPAC 2007



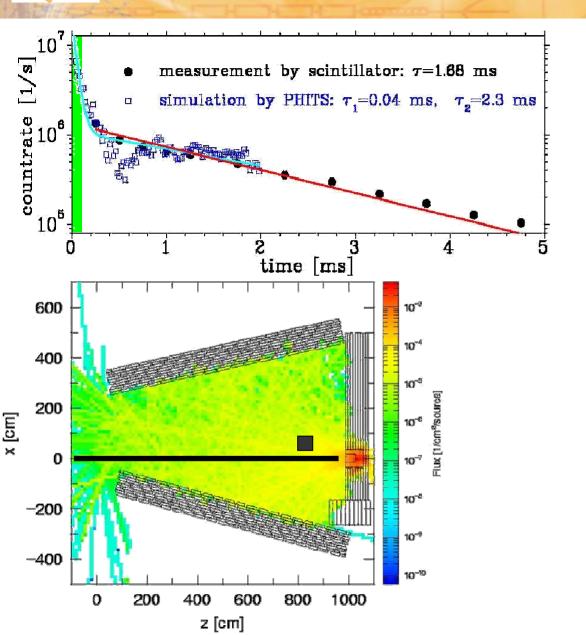
Energy Variation



19



Background Distribution



- Neutron 'afterglow' longer than µs beam delivery
- Simulation and experiment agree well!
- ⇒ Reduction by short gating (improvement: factor 4)

Simulation by PHITS:

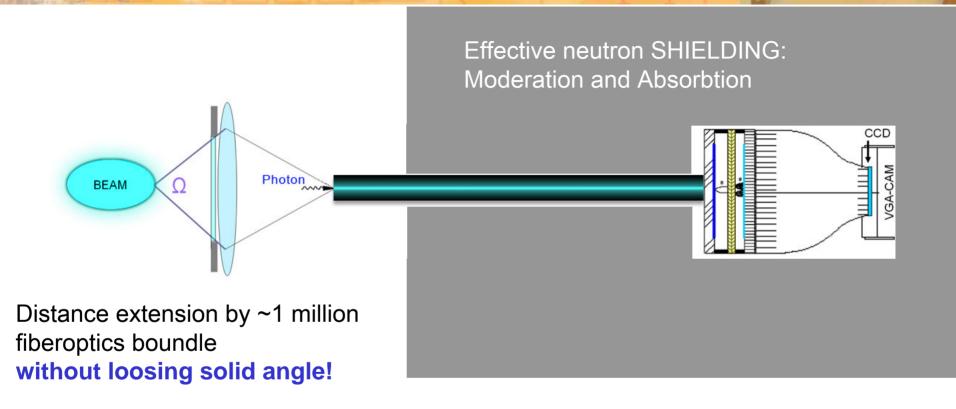
- Neutrons are backscattered from walls
- Neutron flux in whole cave
- ⇒ Reduction by moderation and absorbtion in shielding





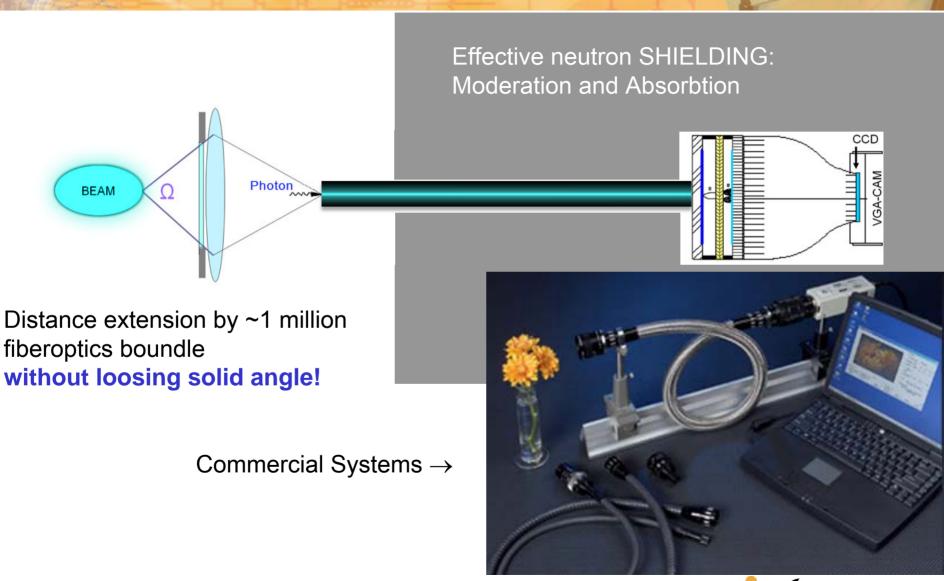
Shielding Concept





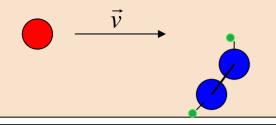


Shielding Concept





How Excitation affects Profiles



$$N_2(X^1\Sigma) + Ion$$



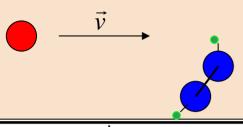
$$N_2^+(B^2\Sigma_u^+) + e^- + Ion$$



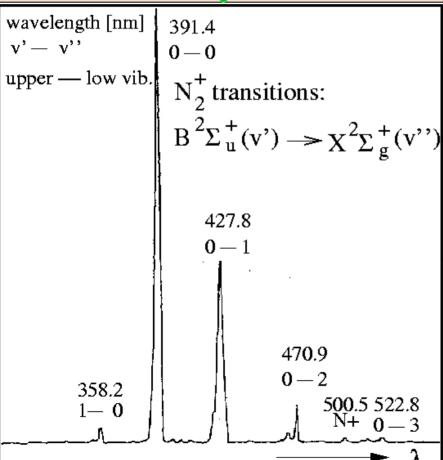
$$N_2^+(X^2\Sigma_g^+) + \gamma(390 \le \lambda \le 471nm)$$



How Excitation affects Profiles



$$N_2(X^1\Sigma) + Ion$$



$$N_2^+(B^2\Sigma_u^+) + e^- + Ion$$

$$N_2^+(X^2\Sigma_g^+) + \gamma(390 \le \lambda \le 471nm)$$

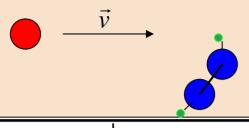
Vibrational spectrum [Huges, Philpot 1961] for 100 keV protons.

Strongest lines at 391,4 nm and 427,8 nm. Optical glasses + photocathode have to be UV-enhanced. ~60 ns lifetime.

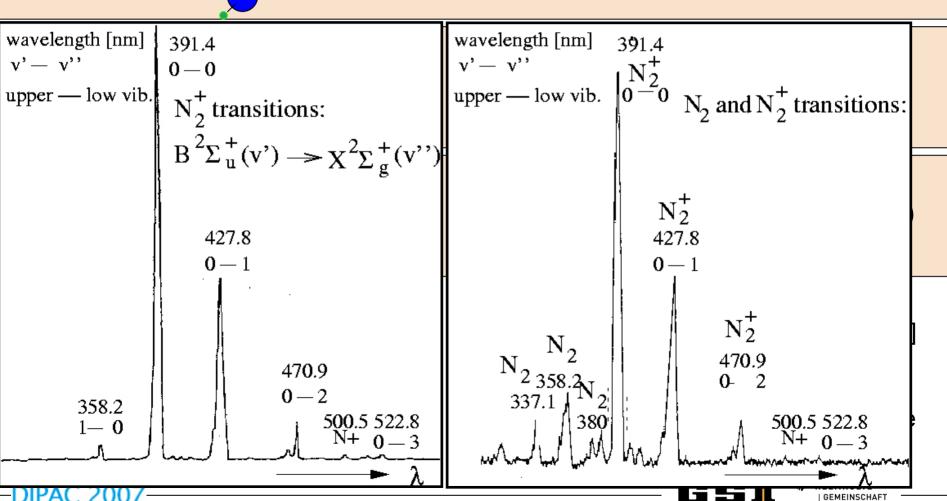




How Excitation affects Profiles

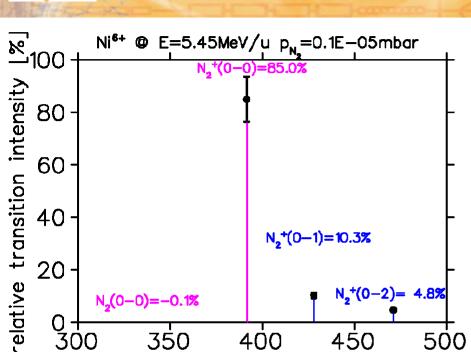


$$N_2(X^1\Sigma) + Ion$$

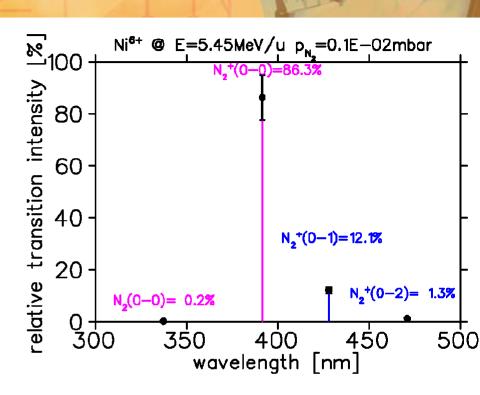




Fluorescence Levels



wavelength [nm]



Contribution of fluorescence levels remains constant up to p=10⁻³ mbar

Contribution by 2-step excitation can be neglected!







Conclusion



- General functionality of BIF had been proven!
 - Profile determination in SINGLE PASS MODE!
- Careful investigation concerning:
 - Signal strength → linear with p, Bethe-Bl. with E
 - Profile width → constant with p
 - Background contribution → ~E², neutron shielding
 - Fluorescence levels → even for high p no distortion
- Future Improvements:
 - Optimizing geometry, lens, intensifier and camera
 - Development of shielding using fiberoptics bundle
 - Further investigation to establish BIF as standard tool!







Thank You ©



